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United States Patent [19]

Bagnal

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[54] STACK THICKNESS MEASURING GAUGE

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[73] Assignee: Charles W. Goff; a part interest

[**] Term: 14 Years

[21] Appl. No.: 29/096,899

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[51] LOC (6) Cl. 10-04

[52] U.S. Cl. D10/64

[58] Field of Search D10/64, 65; 33/832-836, 33/794

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Primary Examiner—Antoine Duval Davis

[57] CLAIM

The ornamental design for a stack thickness measuring gauge, as shown and described.

DESCRIPTION

FIG. 1 is a perspective view of a stack thickness measuring gauge, as seen from the front and one side, showing my new design;

FIG. 2 is an elevational view thereof, as taken from the other side, the two sides being mirror images of each other;

FIG. 3 is is a top plan view thereof;

FIG. 4 is a front elevational view thereof;

FIG. 5 is a rear elevational view thereof; and,

FIG. 6 is a bottom plan view thereof.

Being shown in an arbitrary orientation for illustrative purposes, the stack thickness measuring gauge is useful also in different orientations. In FIG. 1, broken-line showings of a user's hand and of a stack of sheets are for illustrative purposes only and form no part of the claimed design.

1 Claim, 1 Drawing Sheet

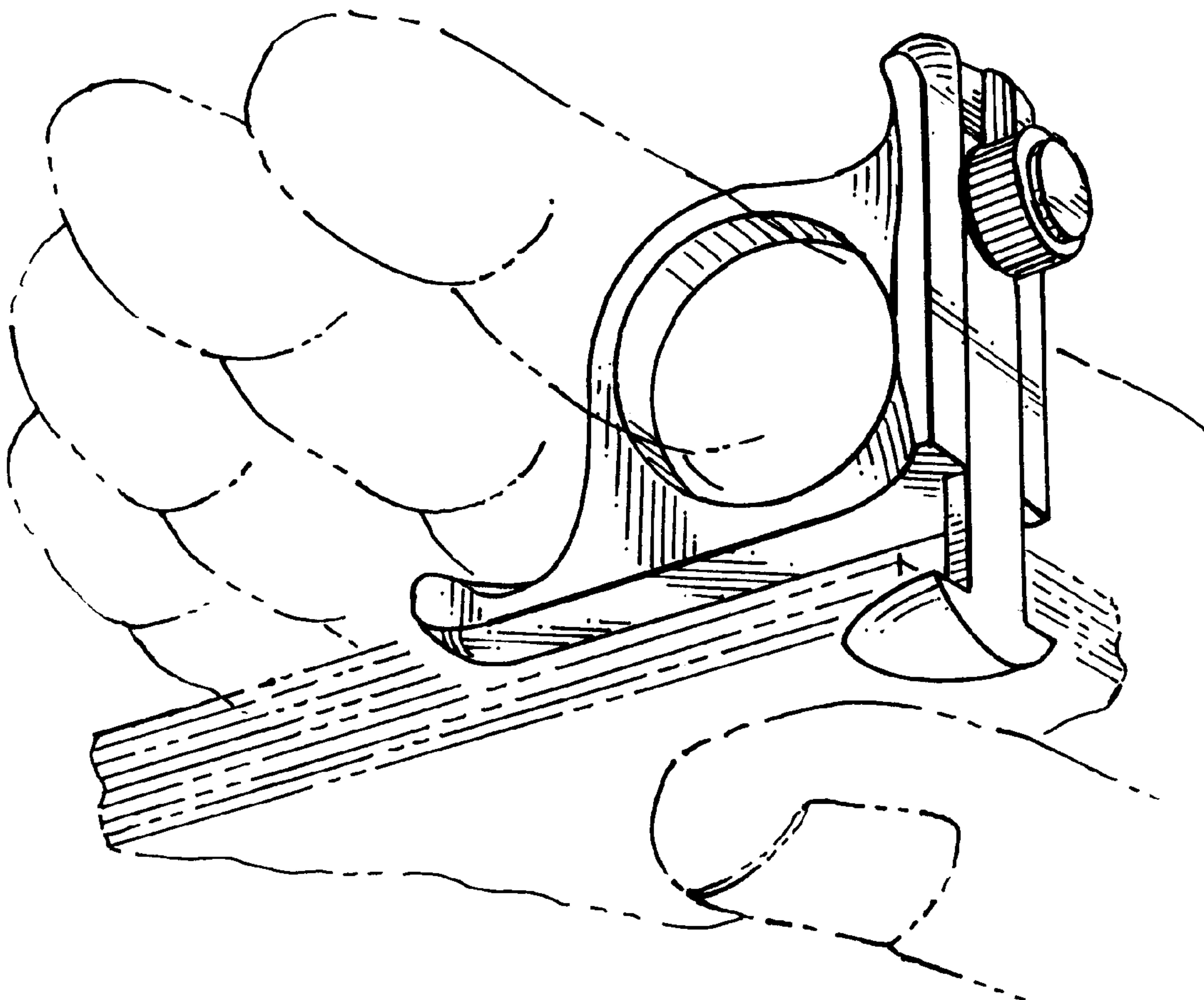


FIG. 1

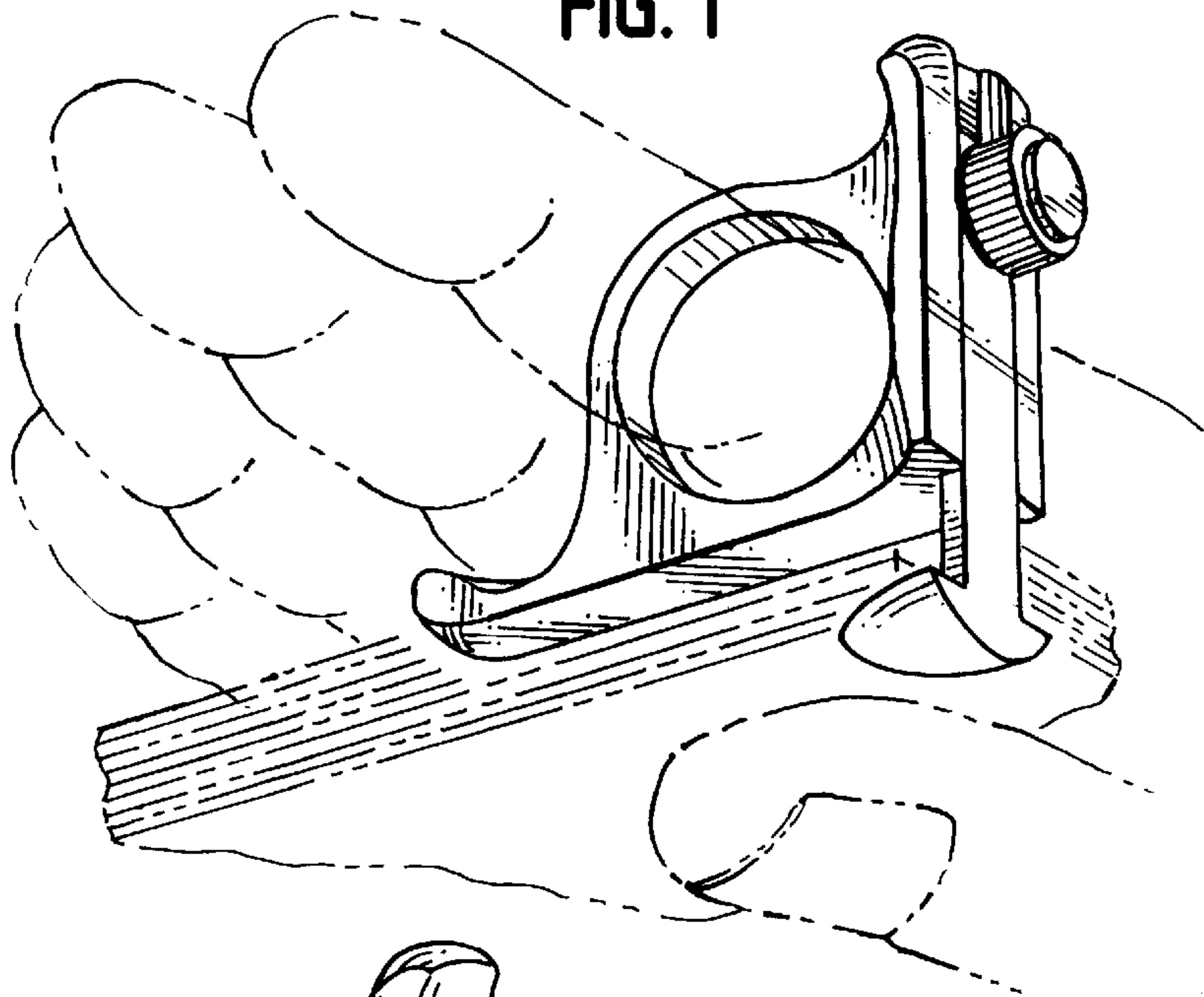


FIG. 3

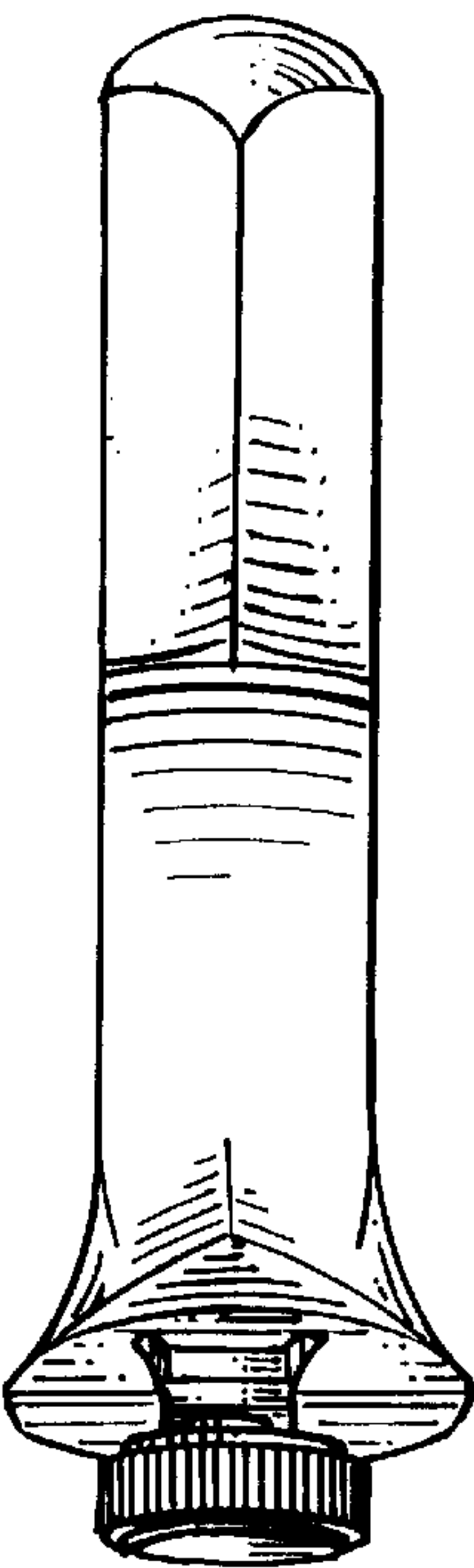


FIG. 2

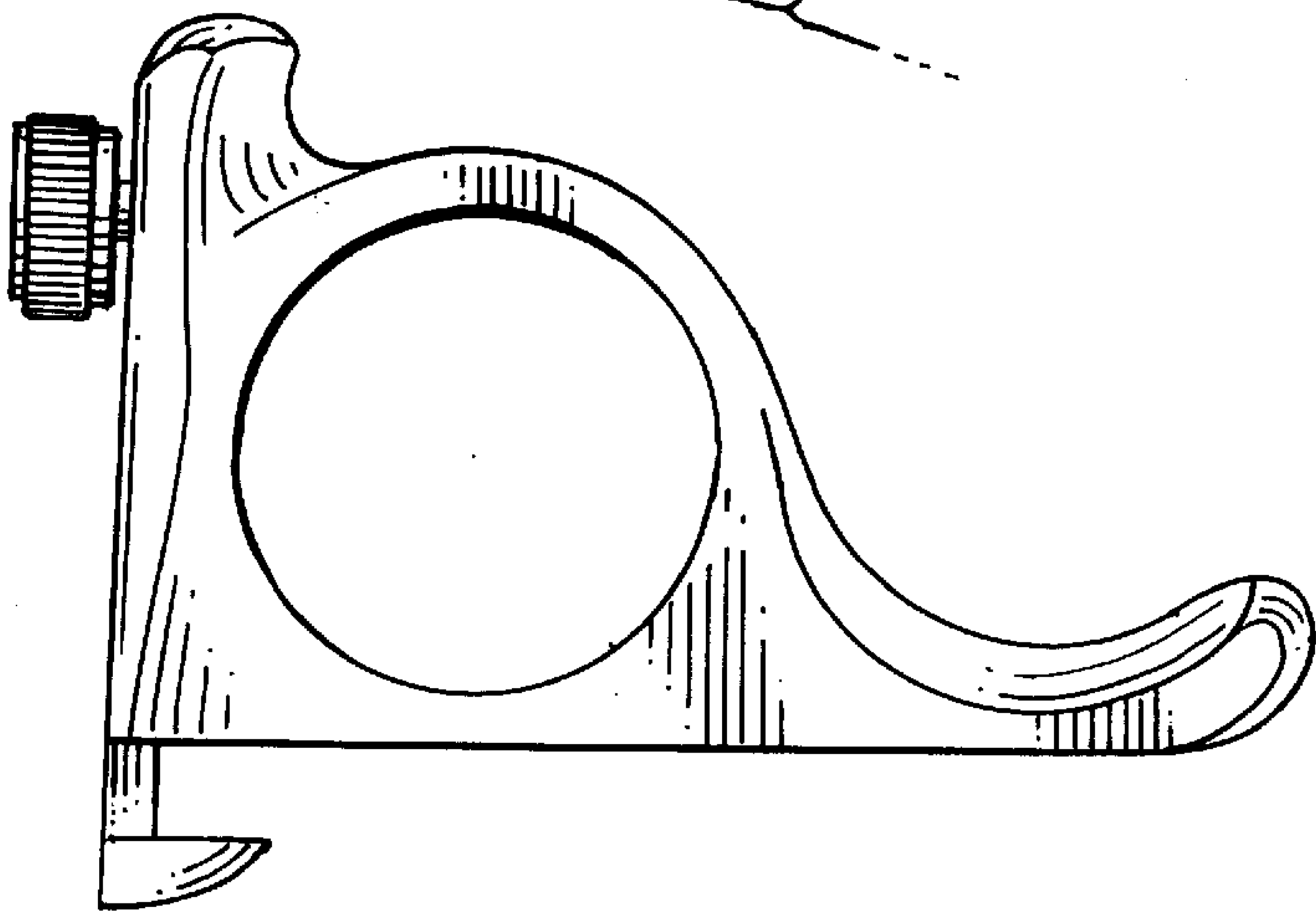


FIG. 6

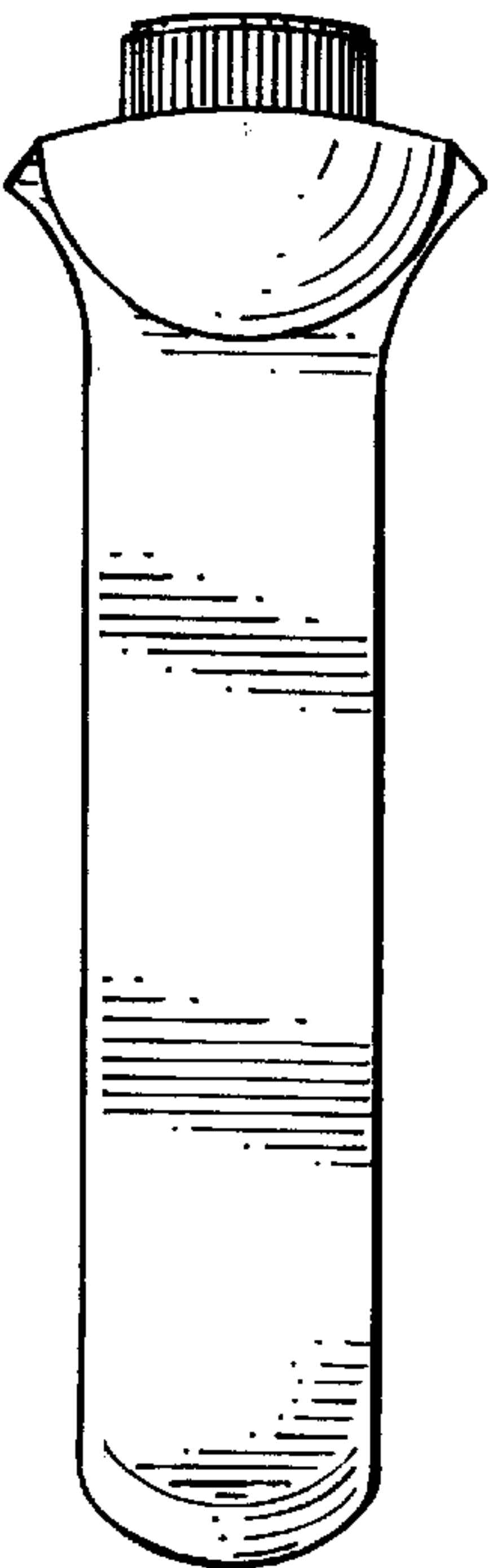


FIG. 4

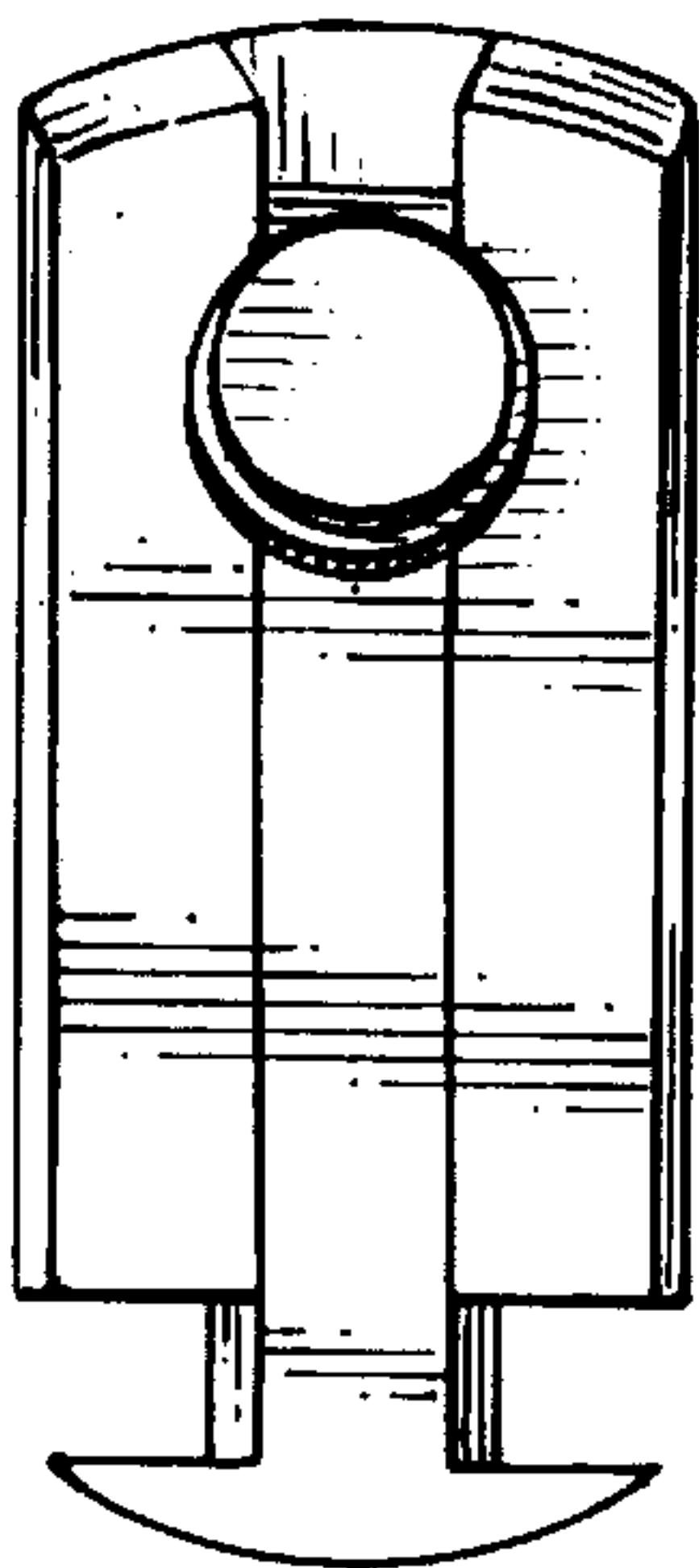


FIG. 5

